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Ujwala M. Pagar

In recognition of the publication of the paper entitled

Influence of annealing on electrical and optical properties of NiO thick film Sensors developed by screen printing technique

Published in Volume 7 Issue 2, February-2022, | Impact Factor: 9.15 by Google Scholar

Co-Authors - U. P. Shinde

Paper ID - IJSDR2202014 Registration ID - 193966





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